This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

Claims 1 and 2 (canceled)

Claim 3 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein said piezoelectric thin film contacts at least one of said substrate and said comb electrodes at the negative surface thereof.

Claim 4 (currently amended): A surface acoustic wave device in accordance with ~~any one of~~ claim ~~1~~6, further comprising a short-circuit electrode disposed on said piezoelectric thin film.

Claim 5 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein the Euler angles of said quartz substrate are within the range such that the power flow angle PFA of a Rayleigh wave is within about ± 2.5°.

Claim 6 (currently amended)~~6. A surface acoustic wave device in accordance with claim 1,~~ A surface acoustic wave device, comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within th range such that the

temperature coefficient of frequency TCF of the surface acoustic wave device is within about ± 25 ppm/°C.

Claim 7 (original): A surface acoustic wave device in accordance with claim 6, wherein the Euler angles of said quartz substrate are within the range such that the temperature coefficient of frequency TCF of the surface acoustic wave device is within about ± 5 ppm/°C.

Claim 8 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein the Euler angles of said quartz substrate are within the range such that the electromechanical coupling coefficient for the Rayleigh wave, K^2 is not smaller than about 0.8%.

Claim 9 (previously presented): A surface acoustic wave device comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within the range such that the power flow angle PFA of a Rayleigh wave is within about ± 2.5°; and

the Euler angles of said quartz substrate are within the range such that the electromechanical coupling coefficient for a spurious wave K_{sp}^2 is not larger than about 0.05%.

Claim 10 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein the temperature coefficient of frequency, TCF of said piezoelectric thin film has a negative value.

Claim 11 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein the Euler angles of said quartz substrate are within the range such that the difference in the power flow angle, ΔPFA between the surface acoustic wave to be utilized and the unwanted surface acoustic wave not to be utilized is within about ± 1°.

Claim 12 (currently amended): A surface acoustic wave device in accordance with claim ~~1~~6, wherein said piezoelectric thin film is made of a material selected from the group consisting of ZnO, AlN, Ta_2O_5, and CdS.

Claim 13 (currently amended): A surface acoustic wave device according to claim ~~1~~6, wherein the angle ϕ of the Euler angles (ϕ, θ, ψ) is within a range of -35° to +35°.

Claim 14 (previously presented): A surface acoustic wave device, comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within a range such that the power flow angle PFA of a Rayleigh wave is within about ± 2.5°;

said range of the Euler angles set such that the PFA is within about ± 2.5° is within an area surrounded by lines which are represented by the following equations:

$\theta=201.77292-8.1909*\psi+0.3257*\psi^2-0.00532*\psi^3+0.0000286691*\psi^4$ and $3\leqq\psi\leqq40$;

$\theta=-2.3333*\psi+221.33$ and $40\leqq\psi\leqq43$;

$\theta=-20.667*\psi+1009.7$ and $43\leqq\psi\leqq44.5$;

$\psi=242.92932-2.46296*\theta-0.04285*\theta^2+0.000792121*\theta^3-0.00000316309*\theta^4$ and $60\leqq\psi\leqq106$;

$\theta=60$ and $28\leqq\psi\leqq70$;

$\theta=1.39744*\psi^2-78.37179*\psi+1158.8$ and $27.5\leqq\psi\leqq32$;

$\theta=9.8429+15.55204*\psi-1.0153*\psi^2+0.0306*\psi^3-0.00038175*\psi^4$ and $3\leqq\psi\leqq32$;

$\theta=60$ and $0\leqq\psi\leqq4$;

$\psi=0$ and $60\leqq\theta\leqq180$;

$\theta=180$ and $0\leqq\psi\leqq4$; and

the Euler angles of said quartz substrate are within a range such that the electromechanical coupling coefficient for a spurious wave, K_{sp}^2 is not larger than about 0.05%;

said range of the Euler angles set such that K_{sp}^2 is not larger than about 0.05% is within an area surrounded by lines which are represented by the following equations:

$\theta=461.5-51.23992*\psi+3.55894*\psi^2-0.12153*\psi^3+0.00171*\psi^4$ and $12\leqq\psi\leqq25.5$;

$\theta=-10*\psi+425$ and $24\leqq\psi\leqq25.5$;

$\theta=-88.97104+38.79904*\psi-1.80561*\psi^2+0.03334*\psi^3-0.000217323*\psi^4$ and $27\leqq\psi\leqq43$;

θ=-0.013928594*ψ^4+2.255507173*ψ^3-136.803833233*ψ^2+3684.063042727*ψ-37024.00 and 33$\leqq\psi\leqq$43;

θ=0.0009461088154*ψ^4-0.178399621211*ψ^3+12.5950972795403*ψ^2-395.999782194768*ψ+4763.57 and 33$\leqq\psi\leqq$55;

θ=60 and 29$\leqq\psi\leqq$55;

θ=0.01724063*ψ^3-1.20723413*ψ^2+24.63357158*ψ-58 and 16$\leqq\psi\leqq$30;

θ=0.0139*ψ^2+0.9028*ψ+79 and 79$\leqq\psi\leqq$100;

ψ=0 and 78$\leqq\theta\leqq$180;

θ=180 and 0$\leqq\psi\leqq$13;

θ=180 and 24$\leqq\psi\leqq$29.